

<b>Notice of References Cited</b>		Application/Control No. 10/555,474	Applicant(s)/Patent Under Reexamination MAIER ET AL.	
		Examiner Jeffrey Lenihan	Art Unit 1796	Page 1 of 1

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*	B	US-2006/0167185 A1	07-2006	Fuchs et al.	525/240
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	K	US-			
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	M	US-			

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**NON-PATENT DOCUMENTS**

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